Unit: mm

TOSHIBA Transistor Silicon NPN Triple Diffused Type (PCT Process)

# 2SC5930

High-Speed and High-Voltage Switching Applications Switching Regulator Applications DC-DC Converter Applications

• High-speed switching:  $t_f = 0.3 \mu s \text{ (max) (IC} = 0.3 \text{ A)}$ 

#### Absolute Maximum Ratings (Ta = 25°C)

and estimated failure rate, etc).

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	600	V	
Collector-emitter voltage		V <sub>CEX</sub>	600	V	
Collector-emitter voltage		V <sub>CEO</sub>	285	V	
Emitter-base voltage		V <sub>EBO</sub>	7	V	
Collector current	DC	Ic	1.0	Α	
	Pulse	I <sub>CP</sub>	2.0		
Base current		lΒ	0.5	Α	
Collector power dissipation	Ta = 25°C	PC	1.0	W	
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	

7.1MAX
3.8
3.8
3.2
0.55 - 0.05
0.85
0.45 - 0.05
1 2 3 1.025 ± 0.05
1 2 3 1.025 ± 0.05
1 2 3 Emitter

JEDEC —

JEITA —

TOSHIBA 2-7D101A

Weight: 0.2 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report

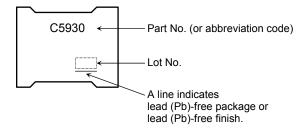
### **Electrical Characteristics (Ta = 25°C)**

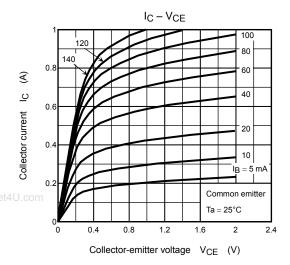
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	V <sub>CB</sub> = 600 V, I <sub>E</sub> = 0	_	_	100	μА
Emitter cut-off current		I <sub>EBO</sub>	$V_{EB} = 7 \text{ V, } I_{C} = 0$	_	_	100	μΑ
Collector-base breakdown voltage		V (BR) CBO	$I_C = 1 \text{ mA}, I_B = 0$	600	_	_	V
Collector-emitter breakdown voltage		V (BR) CEO	$I_C = 10 \text{ mA}, I_B = 0$	285	_	_	V
DC current gain		h <sub>FE</sub> (1)	$V_{CE} = 5 \text{ V}, I_{C} = 1 \text{ mA}$	30	_	100	
		h <sub>FE</sub> (2)	$V_{CE} = 5 \text{ V}, I_{C} = 0.2 \text{ A}$	40	_	100	
Collector-emitter sa	turation voltage	V <sub>CE (sat)</sub>	I <sub>C</sub> = 0.6 A, I <sub>B</sub> = 0.075 A	_	_	1.0	V
Base-emitter saturation voltage		V <sub>BE</sub> (sat)	I <sub>C</sub> = 0.6 A, I <sub>B</sub> = 0.075 A	_	_	1.3	V
Switching time	Rise time	t <sub>r</sub>	See Figure 1. V <sub>CC</sub> ≈ 200 V, R <sub>L</sub> = 667 Ω	_	_	0.5	
	Storage time	t <sub>stg</sub>		_	_	3.0	μS
	Fall time	t <sub>f</sub>	$I_{B1} = 20 \text{ mA}, -I_{B2} = 50 \text{ mA}$	_	_	0.3	

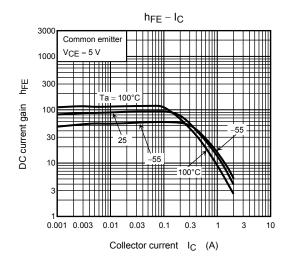
 $\begin{array}{c|c} & V_{CC} \\ \hline 20 \ \mu s \\ \hline \\ I_{B1} \\ \hline \\ I_{B2} \\ \hline \\ Duty \ cycle < 1\% \\ \end{array}$ 

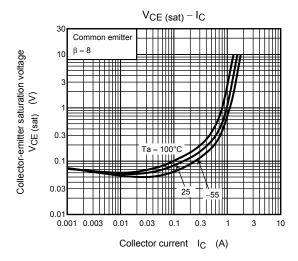
Figure 1 Switching Time Test Circuit & Timing Chart

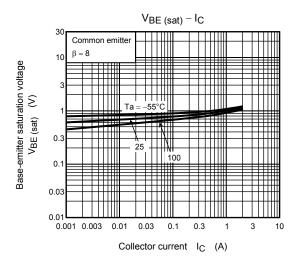
## Marking

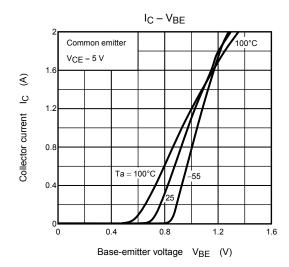


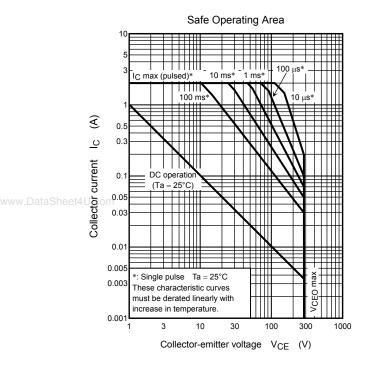












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